# **Supporting information for:**

## In situ synthesis of Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub> heterojunction photocatalysts with

# enhanced visible light responsive activity

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### 1. UV-vis diffuse reflectance spectra



Fig. S1 UV-vis diffuse reflectance spectra (a) thiourea as sulfur source reacted with  $Bi_2SiO_5$  at room temperature for 30 min, (b) thiourea as sulfur source reacted with  $Bi_2SiO_5$  at 60 °C for 3 h, (c) pure  $Bi_2SiO_5$ , (d) cysteine as sulfur source reacted with  $Bi_2SiO_5$  at 60 °C for 3 h, (e) cysteine as sulfur source reacted with  $Bi_2SiO_5$  at 60 °C for 3 h, (e) cysteine as sulfur source reacted with  $Bi_2SiO_5$  at room temperature for 30min and (f) TAA as sulfur source reacted with  $Bi_2SiO_5$  at room temperature for 30 min.

Fig. S1 shows the UV-vis diffuse reflectance spectra of  $Bi_2S_3/Bi_2SiO_5$  heterojunctions forming by different sulfur source and processing conditions. From the picture we can know even improving the reaction time and temperature, the visible light absorption of the samples using thiourea and cysteine as sulfur source is still very low. When TAA was used as sulfur source and the reaction was kept in a short time and room temperature, the visible light absorption of the samples is increased obviously. From the results, the speed of releasing S<sup>2-</sup> can be concluded in the following order: TAA > cysteine > thiourea. So TAA is regarded as the appreciate sulfur source for the preparation of  $Bi_2S_3/Bi_2SiO_5$  heterojunctions.

### 2. XRD pattern



Fig. S2 (a) XRD pattern of pure  $Bi_2SiO_5$  (JCPDS. 36-0287), (b) XRD pattern of  $Bi_2SiO_5$  reacted with TAA solution at 80 °C for 3 h, (c) XRD pattern of pure  $Bi_2S_3$  (JCPDS. 17-0320).

From the picture we can see the diffraction peaks of  $Bi_2S_3$  (JCPDS. 17-0320) appear obviously. This result indicates that the  $Bi_2SiO_5$  can react with TAA to form  $Bi_2S_3/Bi_2SiO_5$  composites, and increased reaction time and temperature can promote the  $Bi_2S_3$  formation.

### 3. The chemical composition and of composite materials

From the EDS spectrum and detailed chemical composition of composite materials of  $Bi_2S_3/Bi_2SiO_5$  composites, the atomic percentage of Bi, O, Si (Bi : O : Si = 2.15 : 1 : 6.19), is approximately corresponded with the stoichiometric ratio of  $Bi_2SiO_5$ . The atomic ratio of sulfur are 0.330%, 0.740% and 1.280% for  $Bi_2S_3/Bi_2SiO_5$ -15 min,  $Bi_2S_3/Bi_2SiO_5$ -30 min, and  $Bi_2S_3/Bi_2SiO_5$ -60 min, respectively. Therefore, the actual molar content of  $Bi_2S_3$  are 0.110%, 0.247% and 0.427%, respectively.



Fig. S3 EDS spectrum and detailed chemical composition of composite materials of Bi<sub>2</sub>SiO<sub>5</sub>.



Fig. S4 EDS spectrum and detailed chemical composition of composite materials of  $Bi_2S_3/Bi_2SiO_5$ -15min heterojunction.

		S	Spectrum 18
0 1 2 3 Full Scale 1910 cts Cursor: 0.000	4 5 6	7 8	9 10 keV
Element	Weight%	Atomic%	-
ОК	15.56	64.05	
Si K	4.29	10.06	
S K	0.36	0.74	
Bi M	79.79	25.15	
Totals	100.00		_

Fig. S5 EDS spectrum and detailed chemical composition of composite materials of  $Bi_2S_3/Bi_2SiO_5$ -30min heterojunction.



Fig. S6 EDS spectrum and detailed chemical composition of composite materials of

 $Bi_2S_3/Bi_2SiO_5$ -60min heterojunction.

#### 4. The calculation of the sizes of Bi<sub>2</sub>S<sub>3</sub> in Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub> heterojunctions

When the size of the semiconductor nanoparticles reduce to 1-10 nm, the quantum confinement will appear,<sup>1</sup> the blue shift of the light absorption will happen and the band gap of the semiconductor is adjustable. The different band gap of the products attribute to the quantum confinement. On the basis of the effective mass approximation model, the relationship between  $\Delta E_g$  and R can be describe by the following equation:<sup>2</sup>

$$\Delta E_g(R) = \frac{\mathbf{h}^2}{8m_0R^2} \left(\frac{1}{m_e^*} + \frac{1}{m_h^*}\right)$$

Eg (R) is the band gap shift, mo the electron mass, h the Planck's constant, R the crystal radius, the

 $m_e^*$  and  $m_h^*$  are the effective masses of electrons and holes, respectively. Through the caculation,  $\Delta E_g$  (R) = 19.4/R<sup>2</sup>, we can get the sizes of Bi<sub>2</sub>S<sub>3</sub> in Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub> heterojunction photocatalysts with different reaction time, 3.41 nm, 3.92 nm and 4.61 nm, respectively. It accord with the conditions of the quantum size.

### 5. The positions of E<sub>CB</sub> and E<sub>VB</sub> of Bi<sub>2</sub>SiO<sub>5</sub> and Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub> heterojunctions

For a semiconductor, the optical absorption near the band edge follows the equation:  $ahv = A(hv-E_g)^{n/2}$ ,<sup>3</sup> in the equation, a is the absorption coefficient, v is light frequency, A is proportionality constant and  $E_g$  is band gap, respectively. The value of n depends on the type of the semiconductor, n=1 for direct transition and n=4 for indirect transition.<sup>4</sup> As reported previously, Bi<sub>2</sub>SiO<sub>5</sub> and Bi<sub>2</sub>S<sub>3</sub> both are direct transition, <sup>5,6</sup> the n values of Bi<sub>2</sub>SiO<sub>5</sub> and Bi<sub>2</sub>S<sub>3</sub> are 1. From the plot of  $(ahv)^2$  - hv, we can estimate the band gap of the products, the  $E_g$  of Bi<sub>2</sub>SiO<sub>5</sub>, Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub>-15 min, Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub>-30 min, Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub>-60 min are 3.76 eV, 2.96 eV, 2.56 eV and 2.21 eV, respectively.  $X_{Bi}$ =4.885,  $X_{Si}$ =4.915,  $X_O$ =7.675,  $X_S$ =6.385, so the X values for Bi<sub>2</sub>SiO<sub>5</sub> and Bi<sub>2</sub>S<sub>3</sub> are 6.474eV and 5.276eV. The top of VB of Bi<sub>2</sub>SiO<sub>5</sub> is 3.854eV and the bottom of CB is 0.094eV. The values of  $E_{CB}$ ,  $E_{VB}$  and  $E_g$  of Bi<sub>2</sub>S<sub>3</sub>/Bi<sub>2</sub>SiO<sub>5</sub> heterojunctions are listed in Table S1.

Semiconductor	$E_{CB} (eV)$	$E_{VB}(eV)$	E <sub>g</sub> (eV)
Bi <sub>2</sub> S <sub>3</sub> in Bi <sub>2</sub> S <sub>3</sub> /Bi <sub>2</sub> SiO <sub>5</sub> -15min	-0.704	2.256	2.96
Bi <sub>2</sub> S <sub>3</sub> in Bi <sub>2</sub> S <sub>3</sub> /Bi <sub>2</sub> SiO <sub>5</sub> -30min	-0.504	2.056	2.56
$Bi_2S_3$ in $Bi_2S_3/Bi_2SiO_5$ -60min	-0.329	1.881	2.21

Table S1. The values of  $E_{CB}$ ,  $E_{VB}$  and  $E_g$  of  $Bi_2S_3$  in  $Bi_2S_3/Bi_2SiO_5$  heterojunctions.

#### 6. The BET surface areas of the samples

Nitrogen adsorption and desorption measurement was used to study the Brunauer–Emmett–Teller (BET) surface areas of the samples, Table S2 shows the BET surface areas of the samples. It shows that the surface areas of the samples are almost the same, because the content of  $Bi_2S_3$  is very low.

sample	Bi <sub>2</sub> SiO <sub>5</sub>	$Bi_2S_3/Bi_2SiO_5-15min$	$Bi_2S_3/Bi_2SiO_5$ -30mi	$Bi_2S_3/Bi_2SiO_5$ -60min	
			n		
BET surface area(m <sup>2</sup> /g)	22.489	24.606	23.524	24.307	

Table S2. The BET surface areas of the samples.

## Notes and references

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